

# **Notice of References Cited**

Application/Control No.

10/822,005

Applicant(s)/Patent Under  
Reexamination  
ABE ET AL.

Examiner

TUAN N. NGUYEN

Art Unit

2828

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## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,660,410	12-2003	Hosokawa, Chishio	428/690
*	B	US-5,260,963	11-1993	Baird et al.	372/95
*	C	US-6,687,266	02-2004	Ma et al.	372/7
*	D	US-6,262,441	07-2001	Bohler et al.	257/103
*	E	US-2002/0071963	06-2002	Fujii, Hiroyuki	428/690
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
*	U	□□CHEN F et al., "TRIPLET EXCITON CONFINEMENT IN PHOSPHORESCENT POLYMER LIGHT-EMITTING DIODES", APPL. PHYS. LETT. (APPLIED PHYSICS LETTERS), February 17, 2003, Vol. 82, No. 7, pp. 1006-1008
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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